

## STIC EIC 2100 |82\_ Search Request Form |0797/

USPTO	Jeai CII	Request Form	10797/
Today's Date:	What da	te would you like to use to lir Date: May 22,200/ Other	
Senal # 09   Is this a "Fast & Focused" Sear	Examiner # 784/4  Phone 65-4356  862,524  Used" Search Request? (Circle of the in 2-3 hours (maximal of the criteria are posted in FIC2100 and the criteria are posted in FIC2	Format for Search Results PAPER DISK Where have you searched so the DWPI EPO JOO IEEE INSPEC SPI O	(Circle One):  EMAIL  SO far?  ACM IEM TOB  ther
	, motivation, utility, or other specific onyms, keywords, acronyms, defin a copy of the abstract, background, nd.		
Voeal index Non- Let	NJ 110	use tive mo	•
STIC Searcher <u>Teves</u> Pate picked up ///o/o		Phone 308-7795	



## **EIC 2100**

Questions about the scope or the results of the search? Contact the EIC searcher or contact:

Anne Hendrickson, EIC 2100 Team Leader 308-7831, CPK2-4B40

Voluntary Results Feedback Form	
> I am an examiner in Workgroup: Example: 2100	
> Relevant prior art found, search results used as follows:	
☐ 102 rejection	
103 rejection	
☐ Cited as being of interest.	
Helped examiner better understand the invention.	
Helped examiner better understand the state of the art in their technology.	
Types of relevant prior art found:	
☐ Foreign Patent(s)	
<ul> <li>Non-Patent Literature         (journal articles, conference proceedings, new product announcements etc.)     </li> </ul>	
> Relevant prior art not found:	
Results verified the lack of relevant prior art (helped determine patentability).	
Results were not useful in determining patentability or understanding the invention.	
Comments:	

Drop off or send completed forms to STIC/E1C2100 CPK2-4B40

